

Application/Control No.	Applicant(s)/Patent under Reexamination	·
10/661,314	SHI ET AL.	
Examiner	Art Unit	
William J. Deane	2614	

SEARCHED				
21	<del></del>		<u> </u>	
Class	Subclass	Date	Examiner	
378	202.01			
	202.01			
	142.16			
	242			
	386			
	209.01			
	201.01			
		-		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
	_		
	+		
•			